G. PULLA REDDY ENGINEERING COLLEGE (Autonomous): KURNOOL

Accredited by NBA of AICTE and NAAC of UGC

An ISO 9001:2008 Certified Institution

Affiliated to JNTUA, Anantapuramu



Two-Year M. Tech Degree Program M.Tech Scheme & Syllabus - Scheme 2022 (VLSI and Embedded Systems)

DEPARTMENT OF ELECTRONICS AND COMMUNICATION ENGINEERING TWO YEAR M. TECH DEGREE PROGRAM Scheme of Instruction and Examination (Effective from 2022-2023)

S. No.	Category	Course Title	L	Т	Р	Credits	End Exam Marks	CIA Marks	Total
Ι		Theory							
1.	PC	Digital VLSI Design	3	-	-	3	60	40	100
2.	PC	Advanced Embedded Systems	3	-	-	3	60	40	100
3.	PC	Advanced Digital System Design Using Verilog	3	-	-	3	60	40	100
4.	PE	Professional Elective – I	3	-	-	3	60	40	100
5.	PE	Professional Elective – II	3	-	-	3	60	40	100
6.	MC	Research Methodology & IPR	2	-	-	2	-	100	100
7.	AC	Audit Course - I	2	-	-	0	-	-	-
II		Practical							
8.	PCL	Advanced VLSI Lab	-	-	3	2	60	40	100
9.	PCL	Advanced Embedded Systems Lab	-	-	3	2	60	40	100
			19	-	6	21	420	380	800

I Semester – VLSI and Embedded Systems (VLSI & ES)

II Semester – VLSI and Embedded Systems (VLSI & ES)

S. No.	Category	Course Title		Т	Р	Credits	End Exam Marks	CIA Marks	Total
Ι		Theory							
1.	PC	Analog IC Design	3	-	-	3	60	40	100
2.	PC	Embedded Systems for Internet of Things		-	-	3	60	40	100
3.	PE	Professional Elective – III	3	-	-	3	60	40	100
4.	PE	Professional Elective – IV	3	-	-	3	60	40	100
5.	PE	Professional Elective – V	3	-	-	3	60	40	100
6.	AC	Audit Course - II	2	-	-	0	-	-	-
II		Practical							
7.	PCL	Advanced Electronic Design Automation Lab	-	-	3	2	60	40	100
8.	PCL	Embedded IoT Lab	-	-	3	2	60	40	100
			17	-	6	19	420	280	700

Scheme – 2022

Scheme – 2022

DEPARTMENT OF ELECTRONICS AND COMMUNICATION ENGINEERING TWO YEAR M. TECH DEGREE PROGRAM Scheme of Instruction and Examination (Effective from 2022-2023)

III Semester – VLSI and Embedded Systems (VLSI & ES)

S. No.	Category	Course Title	L	Т	Р	Credits	End Exam Marks	CIA Marks	Total
1.	OE	Open Elective (OE) *	2	-	-	2	_	-	100
2.	PR	Dissertation Phase – I	-	-	20	10	-	100	100
3.	CAA	Co – Academic Activities	-	-	-	2	_	100	100
	Total		2	-	20	14	-	200	300

*Open Elective will be offered through MOOCs

IV Semester – VLSI and Embedded Systems (VLSI & ES)

S. No.	Category	Course Title	L	Т	Р	Credits	End Exam Marks	CIA Marks	Total
1	PR	Dissertation Phase - II	-	-	32	16	60	40	100

Scheme – 2022

Scheme – 2022

List of Professional Elective Courses

Description	Subject Title
	Hardware Algorithms for Computer Arithmetic(HACA)
PE - I	Scripting Languages for VLSI Design Automation (SLVA)
	VLSI Technology (VTECH)
	Embedded Programming (EP)
PE - II	Embedded System Architecture (ESA)
	Hardware Software Co-design (HSC)
	Physical Design Automation(PDA)
$\mathrm{PE}-\mathrm{III}$	CAD for VLSI Design(CVD)
	Mixed Signal Circuit Design(MSCD)
	Embedded Networks and Protocols (ENP)
PE - IV	Microcontrollers for Embedded System Design(MESD)
	Principles of Distributed Embedded Systems (PDES)
	VLSI Design For Testability(VDFT)
PE - V	Memory Design and Testing(MDT)
	VLSI Signal Processing (VS)

Open Elective

OE	Open Elective will be selected through MOOCs
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List of Audit Courses

Description	Subject Title
	Disaster Management
Audit Course – I	English for research Paper Writing
	Sanskrit for Technical Knowledge
	Pedagogy Studies
Audit Course – II	Personality Development through Life Enlightenment Skills
	Stress Management by Yoga

I Semester – VLSI and Embedded Systems (VLSI & ES)

Scheme – 2022

S. No.	Category	Course Title	L	Т	Р	Credits	End Exam Marks	CIA Marks	Total
Ι		Theory							
1.	PC	Digital VLSI Design	3	-	-	3	60	40	100
2.	PC	Advanced Embedded Systems	3	-	-	3	60	40	100
3.	PC	Advanced Digital System Design Using Verilog	3	-	-	3	60	40	100
4.	PE	Professional Elective – I	3	-	-	3	60	40	100
5.	PE	Professional Elective – II	3	-	-	3	60	40	100
6.	MC	Research Methodology & IPR	2	-	-	2	-	100	100
7.	AC	Audit Course - I	2	-	-	0	-	-	-
II		Practical							
8.	PCL	Advanced VLSI Lab	-	-	3	2	60	40	100
9.	PCL	Advanced Embedded Systems Lab	-	-	3	2	60	40	100
			19	-	6	21	420	380	800

DIGITAL VLSI DESIGN (DVD)

I Semester :VLSI & ES						Scheme :	2022
Course Code	Hours	/Week		Credits	Maximum Mar	ks	I
EC 851	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAI
	3	-	-	3	40	60	100
Sessional Exam Duration	-					m Duration: 3 E	
Course Outcomes : At t	he end of the	he cours	se the s	student will			
CO1: Analyze the MOSFE	T based cir	cuits ar	nd their	synthesis			
CO2:Draw the layout/stick				•			
CO3:Analyze the performa	•		•				
CO4: Design CMOS combi							
COT. Design Childs comb	mational a	na ayna		0	NT.		
Dania MOSEET Chamantani	tion The	ashald V		ODUCTIO		Valta an Charact	aniation
Basic MOSFET Characteria Square-Law Model, MOSF							
Scaling Theory – Full-Volt							
	с .	-			<u> </u>		•
					SWITCHING PR		<u>Q</u> , 1
CMOS fabrication processi							.Static and
dynamic characteristics of l					Ũ		
					S LOGIC ELEM		
Basic Circuit and DC Oper							
Switching Characteristics,							
Capacitance, Inverter Desig						icitive Loads.CM	US NAND
Gate, CMOS NOR Gate, C						uro	
					DIGITAL CIRCU		hine Derre
Dynamic Power Dissipation Dissipation, Static Power D							ning Powe
Dissipation, State 1 ower D DYNAMIC LOGI	-						IFC
Charge Leakage, charge Sh							
Logic, Single-Phase Logic. Modeling of the Interconne	Issues in C	hip Des	sign:ES	SD Protectio	on, On-Chip Interc		
Text Books :				on, mpur o			
1.Kang, S. and Leblebici, Y	CMOS	Divital 1	Integra	ted Circuite	- Analysis and D	esion Tata McGr	awHill
(2008) 3rd	., CIVIOS	l'ignal .	incgra	acu encuns	¹ marysis and D		a vv 1 1111
2. J P Uyemura, CMOS Cir	cuit Desio	n. Sprir	ger				
Reference Books :		,	8.1				
1.Weste, N.H.E. and Eshr	aghian. K	CMC	DS VL	SI Design:	A Circuits and S	Systems Perspecti	ve. Editio
Wesley (1998) 2nd ed.		.,		21 2 001811		jstems i enspeen	
2. Baker, R.J., Lee, H. W	and Boy	ce. D. F	E., CM	OS Circuit	Design, Lavout an	nd Simulation. W	ilev - IEE
Press (2004) 2nd ed.			· · · ·		8, ,	····· , ···	- 5
3.Weste, N.H.E., Harris, D.	and Bane	rjee, A.	CMO	S VLSI Des	ign, Dorling Kind	ersley (2006) 3rd	ed.
4Rabaey, J.M., Chandrak		-					
				, 8			r · · r
•							
Pearson Education (2007) 2							
Pearson Education (2007) 2 Question Paper Pattern:		aper sha	all con	sist of Six au	estions out of which	ch the student sha	ll answer
Pearson Education (2007) 2		aper sh	all con	sist of Six qu	estions out of whic	ch the student sha	ll answer
Pearson Education (2007) 2 Question Paper Pattern: Internal Assessment: The	question p	•		•			

ADVANCED EMBEDDED SYSTEMS (AES)

I Semester :VLSI & ES						Scheme	: 2022
Course Code	Hours/	Week		Credits		ximum Marks	T
EC 852	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
	3	-	-	3	40	60	100
Sessional Exam Durat	tion : 2 H	rs			-	m Duration: 3	
Course Outcomes : At			urse t	he student			
CO1: Understand features						ems	
CO2: Understand the cate				* *			
CO3: Analyze the architec	-				<u> </u>		
CO4: Utilize the program				* *			
CO5: Create application i	<u> </u>					microcontroller	s
		_	_		ded systems		~
Background and History					-	n. Programming	languages
for embedded systems.							
Processor selection for							
memory to program segn		-		•	-	,	
				oller and o			
Microprocessors Vs Micr	rocontrol					ctions, Address	sing Mode
Instruction Set. The extern							
Serial interface.						1	· 1
	Ar	chitectu	ire of	the MSP4	30 Processor:		
Central Processing Unit,	Addressi	ng Mod	les, C	ConstantGer	nerator and Emula	ted Instructions	, Instructio
Set, Examples, Reflection	is on the	CPU an	d Ins	tructionSet	, Resets, Clock Sy	stem, Memory a	and memor
Organization.							
					nd Displays:		
Parallel Ports, Digital Inpu	uts, Switc	h Debo	unce,	Digital Ou	tputs, Interface bet	ween Systems,	Driving
Heavier Loads, Liquid Cry	ystal Disp	olays, Si	imple	Applicatio	ons of the LCD.		
				30 Case St			
Introduction to Code Com	nposer stu	dio (CC	C Stud	lio Ver. 6.1) a tutorial, A Stud	y of blinking LI	ED,
Enabling LED using Swite					D interfacing, Inte	rrupts, Analog t	o Digital
Conversion, General Purp	ose input	and out	tput p	orts, I2C.			
Text Books :							
1. Raj Kamal, Embeddec	1 Systems	Archite	ecture,	Programm	ing and Design,2 nd	Edition, TMH, 2	006.
2.John H. Davies, MSP430							
				,	····,	1,0	
Reference Books :							
1.Frank Vahid, Tony I	D. Givarø	is, "Em	bedde	ed system I	Design: A Unified I	Hardware/Softw	are
Introduction", John Wily	-			<u>j</u>			
, , , , , , , , , , , , , , , , ,							
Web Reference							
https://onlinecourses.nptel.a	ac.in/noc1	2cs11/c	ourse				
Question Paper Pattern:				-			
Internal Assessment:Th		n paper	shall	consist of	Sixquestions out of	which the stude	ent
shallanswer any Four qu	-		2				*
shahanswer any rour qu							

End Exam: The question paper shall consist of **Eight** questions out of which the student shall answerany **Five** questions

ADVANCED DIGITAL SYSTEM DESIGN USING VERILOG (ADSD)

Semester :VLSI & ES						Scheme : 2	2022
Course Code	Hours/	Week		Credits	Maximum Marks		-
					Continuous		TOTAL
EC 852	L	Т	Р	C	Internal	End Exam	IUIAL
				-	Assessment		
	3	-	-	3	40	60	100
Sessional Exam Duration		1 C (1		.1 .	1	End Exam Du	ration: 3 H
Course Outcomes : A					ient will be able to		
CO1: Analyze and d					1 1		
CO2: Analyze and d					digital circuits		
CO3: Design using p	-		-		£ 41		
CO4: Identify the red							
CO5: Design and use						uits of industry	standards
					UIT DESIGN	. 1.	11
Analysis of clocked s	•		1		0	0,	,
state table assignmen				0	· 1	ntial circuits	design of
iterative circuits-ASM						GIGN	
					AL CIRCUIT DE		•
Analysis of asynchro							
transition table and pro							
dynamic and essentia					rs – mixed operat	ing mode asy	nchronous
circuits – designing ve							
					BILITY ALGOR		T. 1
Fault table method-path							
techniques – The compac							in sell test
					ROGRAMMABLI		
Programming logic devi							LA/PAL –
Realization of finite state					NG VERILOG	IIIX 4000	
Hardwara Madalling wit						Operators For	Modelling
Hardware Modelling wit in Verilog HDL - Behav							
-		-		-			
Finite State Machines– bench - Realization of co							
sequential machine – ser			-			-	
Text Books :	lai auuc		upner		- Design of simple	meroprocesse	<i>л</i> .
2. Charles H.Roth .	In "Fund	omonto	la of I	Logio Dosi	an" Thomson Loss	ming 2004	
3. Nripendra N Bis				-	-	-	
Reference Books :	was Lu	igic Des	ign i	neory rie		,2001	
	Coult Tol	orant or	d For	ult Tostabl	e Hardware Design	" D S Dublicat	ions 2002
-					D" B S Publication		10115,2002
3. M.D.Ciletti ,Mo							Drantica
J. WI.D.Chetti , WIO	uening, .	5 ynthes	is and	i Kapiu i N	Storyping with the	vernog HDL, i	Tentice
Hall 1000							
Hall, 1999. 4 S. Palnitkar, Ve	rilog U		Guid	e to Digita	Design and Sunth	lesis Pearson	2003
4. S. Palnitkar, Ve		DL – A	Guid	e to Digita	l Design and Synth	nesis, Pearson ,	2003.
4. S. Palnitkar , Ve Question Paper Patter	m:						
4. S. Palnitkar , Ve Question Paper Patter Internal Assessment: T	n: The ques	tion pap					
4. S. Palnitkar , Ve Question Paper Patter	r n: The ques questions	tion par	oer sh	all consist	of Six questions out	t of which the s	tudent

ADVANCED VLSI LAB

						Scheme :	2022		
Course Code	Hours	/Week		Credits	Maximum Marks				
EC 860	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL		
	-	-	3	2	40	60	100		
End Exam Durati	on: 3 Hrs				-	•			
Course Outcomes	: At the end of	of the course th	ne stud	ent will b	be able to				
CO1: Analyze H	IDL program	ning models.							
CO2: Design va	rious digital c	ircuits using F	PGA d	levices					
CO3: Synthesize	e various Digi	tal circuits.							
CO4: Design Pla	acement & Ro	uting Techniq	ues						
_		LIST OF	EXP	ERIME	NTS	_			
I					I	I			
. Digital Circu	its Descriptio	n using Verilo	g						
. Verification	of the Function	onality of Desi	igned c	circuits u	sing function Si	mulator.			
. Timing simu	lation for crit	cal path time of	calcula	tion.					
Synthesis of	Combination	al Digital circu	its						
	f Sequential D	0							
b. Place and Ro	oute technique	s for major FP	GA ve	endor suc	ch as Xilinx				
-		ed Digital Circ		-	A devices				
B. Digital Circu	its Descriptio	n using VHDI	_/Veril	og					
nternal Assessmer	nt:40M								
End Exam: 60M									

ADVANCED EMBEDDED SYSTEMSLAB (AES(P))

ISemester :VLSI & ES						Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	ximum Marks	
EC 861	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
	0	0	3	2	40	60	100
End Exam Duratio	n: 3 Hrs						
Course Outcomes : A	At the end	of the c	course	the studen	t will be able to		
CO1: Interpret the level	· ·						
CO2: Interface the I/O	<u> </u>						
CO3:Interface the sense							
CO4:Interface co proce	ssing devi	ices wit					
1. Utilization and Prac	ctice of C	ode Cor		of Experin	ients		
 Interfacing on boar 			-		controller		
 Interfacing on boar Interfacing on boar 						r	
 Interfacing Arrays 	-	-				L	
5. Interfacing Motor a	-						
 6. Interfacing onboard 							
7. Interfacing external							
8. Interfacing displays							
9. Interfacing multiple							
10. Interfacing a sub co						troller	
			•				
Internal Assessment: 4	-0M						
End Exam:60M							

Scheme : 2022 I Semester :VLSI & ES **Course Code Hours/Week Maximum Marks** Credits **Continuous** EC 854 Т L Р С Internal End Exam TOTAL (Professional Elective -Assessment I) 3 3 40 60 100 --**Sessional Exam Duration : 2 Hrs End Exam Duration: 3 Hrs Course Outcomes :** At the end of the course the student will be able to **CO1:**Understand the Redundant number systems **CO2:**Analyze Algorithms for fast addition **CO3:**Analyze VLSI implementation aspects, High speed multiplication **CO4:** Interpret Algorithms for fast division and impact of hardware technology **Algorithms for Fast Addition** Basic Addition and Counting, Bit-serial and ripple-carry adders, Addition of a constant: counters, Manchester carry chains and adders, Carry-Look-ahead Adders, Carry determination as prefix computation, Alternative parallel prefix networks, VLSI implementation aspects, Variations in Fast Adders, Simple carry-skip and Carry-select adders, Hybrid adder designs, Optimizations in fast adders, Multi-Operand Addition, Wallace and Dadda trees, Parallel counters, Generalized parallel counters, Adding multiple signed numbers. **High-Speed Multiplication** Basic Multiplication Schemes, Shift/add multiplication algorithms, Programmed multiplication, Basic hardware multipliers, Multiplication of signed numbers, Multiplication by constants, Preview of fast multipliers, High-Radix Multipliers, Modified Booth's recoding, Tree and Array Multipliers, Variations in Multipliers, VLSI layout considerations. Fast Division and Division Through Multiplication Basic Division Schemes, Shift/subtract division algorithms, Programmed division, Restoring hardware dividers, Non-restoring and signed division, Division by constants, Preview of fast dividers, High-Radix Dividers, Variations in Dividers, Combined multiply/divide units, Division by Convergence, Hardware implementation. **Digital Input, Output, and Displays:** Square-Rooting Methods, The CORDIC Algorithms, Computing algorithms, Exponentiation, Approximating functions, Merged arithmetic, Arithmetic by Table Lookup, Tradeoffs in cost, speed, and accuracy. **Function Evaluation** Introduction to Code Composer studio (CC Studio Ver. 6.1) a tutorial, A Study of blinking LED, Enabling LED using Switches, UART Communication, LCD interfacing, Interrupts, Analog to Digital Conversion, General Purpose input and output ports, I2C. **Text Books :** 1 .Parhami, B., Computer Arithmetic: Algorithms and Hardware Design, Oxford University Press (2000).2. Ercegovac, M. and Lang, T., Digital Arithmetic, Elsevier (2005). **Reference Books :** 1 .Koren, I., Computer Arithmetic Algorithms, 2nd Edition, Uni Press (2005) 2nd ed. **Question Paper Pattern:** Internal Assessment: The question paper shall consist of Six questions out of which the student shall answer any Four questions End Exam: The question paper shall consist of **Eight** questions out of which the student shall

answer any **Five** questions

Hardware Algorithms for Computer Arithmetic (HACA)

SCRIPTING LANGUAGES FOR VLSI DESING AUTOMATION (SLVA)

I Semester : VLSI & ES	5					Sch	eme : 202
Course Code	Ho	ours/We	ek	Credits	Max	imum Marks	
EC 855 (Professional Elective – I)	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
~	3	-	-	3	40	60	100
Sessional Exam Duratio			- 1	. 1		nd Exam Durat	tion: 3 Hrs
Course Outcomes :At th			irse th	e student w	III be able to		
CO1: scripting the given							
CO2: Utilize Scripting la			: proje	ects.			
CO3: AnalyzeJava Scrip	t, SKIL		•	P • 4• 1			
DEDI Ella handlag	notora (f scripting	8 8	t in data taman d	Ononctore
PERL, File handles, Open Statements and declaration					1	• 1	1
Statements and declaration		pie, con	•	· •			utions
			Patt	ern matchi	ng		
expression, Pattern match	ning ope	erators, C	Charac	eter classes,	Positions, capturir	ng and clustering	g.
			S	ubroutines			
Syntax, Semantics, Prote Hashesof arrays, Hashes	• •					•	•
Process model, Thread r and externals, Internal d perl.				Using debu			
			Ot	ther langua	ges		
Broad features of other	scripting	g languag	ges SI	KILL, CGI,	java script, VB scr	ript	
	Books	:					
Text Books / Reference	~ .	stiansen	, John	Orwant, Pr	ogramming perl, 3	^{3rd} Edition, Orei	lly
1. Larry Wall, To	om Chri						
		om Phoe	enix, <i>L</i>	Learning PE	RL, Oreilly public	ations	
 Larry Wall, To publications Randal L, Sch 	wartz To n:						
 Larry Wall, To publications Randal L, Sch 	wartz To n: The ques	tion pap					udent

VLSI TECHNOLOGY (VTECH)

I Semester :VLSI & ES						Scheme : 20	22
Course Code	Hours/	Week		Credits	Maximum Marks		
					Continuous		
EC 856	L	Т	P	С	Internal	End Exam	TOTAL
(Professional Elective – I)					Assessment		
	3	-	-	3	40	60	100
Sessional Exam Duration :	2 Hrs				End Exam	Duration: 3 Hrs	
Course Outcomes : At the end	l of the co	ourse the	stude	nt will be al	ole to		
CO1: Understand the MOS tec	hnologie	s, its mo	dels ar	nd latch-up	problem		
CO2: Design the layouts of log	gic gates						
CO3: Interpret the stages of ma	anufactur	ing an IC	2				
CO4: Analyze the doping and c	leposition	n procedi	ures				
CO5: Analyze design rules and	scaling,	BICMO	S ICs				
					tion to MOS Tech	<u> </u>	
MOS, CMOS, BiCMOS Tec				-			
Ids – Vds relationships, Three)S & Bi
CMOS Inverters, Zpu/Zpd, M	MOS Tra	ansistor	circui	t model, L	atch-up in CMOS c	rcuits.	
			Layo	ut Design			
Layout Design and Tools: 7	Transisto	r structu	ures, V	Wires and Y	Vias, Scalable Desig	gn rules, Layou	t
Design tools. Logic Gates &	k Layou	ts: Statio	c Con	plementar	y Gates, Switch Lo	gic, Alternative	Gate
circuits, Low power gates, l	Resistive	e and Ind	ductiv	e intercon	nect delays.	-	
`		Stage	es of I	Manufactu	iring		
Overview of semiconducto	r indust	0			0	product trends,	Crystal
growth, Basic wafer fabrica					0	1	•
wafer fabrication operation							
Oxidation and Photolithogr							
Photoresists, physical prop							
process, Hard bake, develop						photo i	ind shing
	mspeet			nd deposit			
Diffusion process steps, de	nosition		0			n implantation.	2 CVD
basics, CVD process steps							
phase epitaxy, molecular be			CVL	systems,	i lasina cimaneco	CVD systems,	v apour
	-		and	Scaling, B	ICMOS ICs		
Design rules and Scaling, BI						, Resistors, capa	citors,
Packaging: Chip characteris							
Text Books :							
1. Peter Van Zant, Microchip	o fabrica	tion, Mo	Graw	Hill, 1997	7		
2. C.Y. Chang and S.M. Sze							
Reference Books :	,		0,7		,		
1. Micro Electronics circuits	Analysi	s and D	esign	2nd Editio	n, Muhammad H R	ashid, CENAGI	Ē
Learning 2011	2		U		,	,	
2. Eugene D. Fabricius, Intr	oduction	n to VLS	SI des	ign, McGr	aw Hill, 1999		
Question Paper Pattern:							
Internal Assessment: The ques	stion pape	er shall c	onsist	of Six ques	tions out of which th	e student shall an	swer any
Four questions							
End Exam: The question pape	r shall co	nsist of	Eight	questions of	out of which the stude	ent shall answer a	ny Five
questions							

EMBEDDED PROGRAMMING(EP)

						Scheme :	2022
Course Code	Hours/	Week		Credits	Maximum Marks	8	1
EC 857					Continuous		
(Professional Elective –	L	Т	Р	С	Internal	End Exam	TOTAL
II))	2			2	Assessment	60	100
Sessional Exam Duration	3	-	-	3	40	Duration: 3 H	100 Inc
Course Outcomes : At the		e course	e the st	udent will		i Duration: 5 h	115
CO1: Analyze C language							
CO2: Utilize Object orienta		• 1	<u> </u>	0	L		
CO3: Apply software mode		1 0			•		
CO4: Analyze Embedded s				t tools			
INTRODUCTION TO AS			-			SENTATION	
Assembly language program and floating point number							
Structures – Unions – Dy							
Structures - Onions - Dy	ynanne i	-		AMMING			linked lists.
Register usage conventions	s – Tvni					on sequencing	– Procedure
call and return – Function				-	-		
Everything in pass by valu							
scheduling	e ren	iporary	vuriu	un tin	eads pre emptre	e kerneis syt	
seneduning	OBJI	ECT O	RIEN	TED PR	OGRAMMING		
Object oriented analysis and						data structures	– examples
			• • • • • • •	is und coji			••••••
	UN	IFIED	MOI	DELING	LANGUAGE		
Connecting the object mod	el with t	he use	case r	nodel – K	ey strategies for o	bject identifica	tion – UML
basics. Object state behavior							
basics. Object state beliavi					of scenarios in the	e definition of	behaviour –
Timing diagrams – Seque	nce diag	grams -	– Eve	nt hierarc			
Timing diagrams – Seque Architectural design in UM	L concu	rrency	design	n – thread	hies – types and s in UML	strategies of o	
Timing diagrams – Seque Architectural design in UM	L concu	rrency	design	n – thread	hies - types and	strategies of o	
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EMBEDDED SYSTEMS ARCHITECTUTRE (ESA)

I Semester : VLSI & ES						Scher	me : 2022
Course Code	Ho	urs/We	ek	Credits	Maxi	mum Marks	
EC 858					Continuous		
(Professional Elective – II)	L	Т	P	С	Internal	End Exam	Total
(1 Tolessional Elective – 11)	3			3	Assessment 40	60	100
	3	-	-	5	40	00	100
Sessional Exam Duration :	2 Hrs				End	l Exam Duratio	on: 3 Hrs
Course Outcomes :At the e	nd of th	e cours	e the s	student wi	ll be able to		
CO1: Understand the Embe	dded Sy	stem M	odels				
CO2: Analyze the typical e	-	-			-		
CO3: Interpret rationale and	-		0	ng embed	ded systems		
CO4: Analyze the Embedde							
					ed systems		
Embedded system model							
embedded board using V							
application specific ISA n	nodels –					level parallelisi	n
				or Hardw			
Internal processor design:						emory – proces	sor
i/o – interrupts – processo	r buses	-	-				
Beard memory DOM D				t Hardwa			
Board memory: ROM – RA							
memory performance – boa bus with components – bus			ation		g – PCI bus example	e miegranng	
r r r r r r r r r r r r r r r r r r r	I		So	oftware			
Middleware and application	s: PPP -	– IP mic	ldlewa	are – UDP	– Java .application	layer: FTP clie	nt SMTP
– HTTP server and client					TT		
	ŀ	Enginee	ring l	ssues Of	Software		
Design and development:	archited	ctural p	attern	s and refe	erence models – cr	eating the arch	itectural
structures – documenting t	the arch	itecture	– an	alyzing ar	d evaluating the ar	chitecture – de	bugging
testing, and maintaining.							
Text Books :							
1. Embedded system a	rchitect	ure, Ta	mmy l	Noergaard	, Elsevier, 2006.		
Reference Books :							
1. Embedded Systems		0			l Ready-To-Use Mo	dules in C, Jean	l
J.Labrosse, The put	blisher,	Paul Te	mme,	2011.			
Question Paper Pattern:	ann a -4 :		ala - 11			formlation (1	lant
Internal Assessment: The		n paper	snall	consist of	Six questions out of	r which the stuc	ient
shall answer any Four quest End Exam: The question p		alloons	ist of	Fight and	stions out of which	the student shall	1
answer any Five questions	aper sn		151 01	Eight que	stions out of which	the student shall	LI
answer any Five questions							

HARDWARE SOFTWARE CO-DESIGN (HSC)

I Semester : VLSI & ES						Scheme	: 2022
Course Code	Hours/	Week		Credits	Maxi	mum Marks	
EC 859 (Professional Elective – II)	L	Т	Р	С	Continuous Internal	End Exam	TOTAL
	3		-	3	Assessment 40	60	100
Sessional Exam Dura	-	- Hrs	•	3		m Duration: 3	
Course Outcomes : At th			rea th	e student v		III Duration. 5	1115
CO1: Understand H/W at							
CO2: Understand H/W at			0		rahitaaturaa		
CO3: Analyze H/W and S							
CO4: Analyze the H/W							
		system		Design Iss	1100		
Co- Design Models, Arch	itaaturaa	Longu				dology Co Su	nthosis
Algorithms: Hardware so							
system co-synthesis	Jitwale	synthesi	s alge	munns. na	iuware-sontware pa	articioning distr.	Iduleu
system co synthesis		Prot	totyn	ing and E	nulation		
Instruction Set: Data Pr	ocessing			<u> </u>		Load Store In	structions
PSR Instructions, Con							
techniques, System Co							
classes, Architecture for							
control), Architecture fo							
			-		bedded Processor		
Modern embedded arch							
practical consideration in					-	·····	
1					l Verification		
Design, co-design, the						coordinating	concurrent
computations, interfacin		-	-		•		
tools, interface verificati		,	U				
		or Syste	m – 1	Level Spec	ification and Desi	gn-I,II	
System – level specif							
bystem level speen			-		for system level	synthesis, sys	stem level
•	Heterog	0	speci		•	•	
specification languages. system and lycos system	-	0	speci		•	•	
specification languages.	-	0	speci		•	•	
specification languages. system and lycos system	l	eneous	_	fications a	nd multi language o	co-simulation, t	he cosyma
specification languages. system and lycos system Text Books :	l	eneous	_	fications a	nd multi language o	co-simulation, t	he cosyma
specification languages. system and lycos system Text Books : 1. Hardware / Software C	l. lo- Desig	eneous	iples	fications an	nd multi language o e – Jorgen Staunstr	co-simulation, t	he cosyma 1f – 2009,
specification languages. system and lycos system Text Books : 1. Hardware / Software C Springer.	l. lo- Desig	eneous	iples	fications an	nd multi language o e – Jorgen Staunstr	co-simulation, t	he cosyma 1f – 2009,
specification languages. system and lycos system Text Books : 1. Hardware / Software C Springer. 2. Hardware / Software	l. lo- Desig	eneous	iples	fications an	nd multi language o e – Jorgen Staunstr	co-simulation, t	he cosyma 1f – 2009,
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specification languages. system and lycos system Text Books : 1. Hardware / Software C Springer. 2. Hardware / Software Academic Publishers. Reference Books :	lo- Desig Co- Des	eneous n Princ: sign - G	iples a	fications an and Practic	nd multi language o e – Jorgen Staunstr neli, Mariagiovanna	co-simulation, t rup, Wayne Wo a Sami, 2002, K	he cosyma lf – 2009, Cluwer
specification languages. system and lycos system Text Books : 1. Hardware / Software C Springer. 2. Hardware / Software Academic Publishers. Reference Books : 1. A Practical Introduction	lo- Desig	eneous n Princ: sign - G rdware/	iples iovan	fications an and Practic ani De Micl vare Co-des	nd multi language o e – Jorgen Staunstr neli, Mariagiovanna sign -Patrick R. Scl	co-simulation, t rup, Wayne Wo a Sami, 2002, K naumont - 2010	he cosyma lf – 2009, Iluwer – Springer
specification languages. system and lycos system Text Books : 1. Hardware / Software C Springer. 2. Hardware / Software Academic Publishers. Reference Books : 1. A Practical Introduction Question Paper Pattern	o- Desig Co- Design on to Ha	eneous n Princ: sign - G rdware/	iples iovan	fications an and Practic ani De Micl vare Co-des	nd multi language o e – Jorgen Staunstr neli, Mariagiovanna sign -Patrick R. Scl	co-simulation, t rup, Wayne Wo a Sami, 2002, K naumont - 2010	he cosyma lf – 2009, Iluwer – Springer
specification languages. system and lycos system Text Books : 1. Hardware / Software C Springer. 2. Hardware / Software Academic Publishers. Reference Books : 1. A Practical Introduction Question Paper Pattern Internal Assessment: T	on to Ha 'he quest uestions	eneous n Princ: sign - G rdware/ ion pape	iples a iovan Softw er sha	fications an and Practic ani De Micl vare Co-des all consist c	nd multi language of e – Jorgen Staunstr neli, Mariagiovanna sign -Patrick R. Scl of Six questions out	co-simulation, t rup, Wayne Wo a Sami, 2002, K naumont - 2010	he cosyma If – 2009, Iluwer – Springer tudent

RESEARCH METHODOLOGY& IPR(RM& IPR)

a a 1	<u>S</u>					Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	cimum Marks	
	-			ζ.	Continuous		
MC 101	L	Т	Р	С	Internal Assessment	End Exam	TOTAL
	2		_	2	100		100
Sessional Exam Dura		<u>-</u> [rs	_			m Duration: -	
Course Outcomes : At			rse the	e student w			0 1115
CO1: Understand overviliterature review of		-			-	nd conduct a	
CO2: Study the data col	lection me	thods a	nd pro	ocess the da	ta statistically.		
CO3: Understand the ba in a research pap		ties of e	stima	tors, analys	e the estimated dat	a and interpret	the data
	Meanin	g, Obje	ective	and Motiv	vation in Research	1	
in Sampling Design, Ch	naracteristi	cs of a (perimental Desi ples and Rando	
Sampling Design. Errors in Measurement,	Mo , Tests of S	easurer ound N	Good nent a Ieasur	Sample De and Scalin rement, Sca	sign, Random San g Techniques aling and Scale Con	nples and Rando	om
Sampling Design.	Mo , Tests of S	easurer ound N ries Ana	Good nent a leasur alysis,	Sample De and Scalin rement, Sca	esign, Random San g Techniques aling and Scale Con on and Extrapolati	nples and Rando	om
Sampling Design. Errors in Measurement,	Mo , Tests of S s, Time Ser	easurer ound N ries Ana Met	Good nent a leasur alysis, thods	Sample De and Scalin rement, Sca Interpolati of Data C	sign, Random San g Techniques aling and Scale Con on and Extrapolati ollection	nples and Rando	niques,
Sampling Design. Errors in Measurement, Forecasting Techniques Primary Data, Question	Ma , Tests of S s, Time Sen nnaire and I	easurer ound N ries Ana Met Intervie	Good ment a feasur alysis, thods ws, C	Sample De and Scalin rement, Sca Interpolati of Data C ollection of cical Proces	sign, Random San g Techniques lling and Scale Con on and Extrapolati ollection f Secondary Data, o ssing	nples and Rando nstruction Technon. Cases and Scheo	niques, dules.
Sampling Design. Errors in Measurement, Forecasting Techniques Primary Data, Question Correlation and Regress	Mo , Tests of S s, Time Ser maire and I naire and I	easurer bound M ries Ana Met Intervie S sis, Me	Good ment a Measur alysis, thods ws, C Statist thod o	Sample De and Scalin rement, Sca Interpolati of Data C ollection or ical Proces	sign, Random San g Techniques aling and Scale Con on and Extrapolati ollection f Secondary Data, o ssing uares, Regression	nples and Rando nstruction Technon. Cases and Scheo Vs. Correlation,	niques, dules.
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Sampling Design. Errors in Measurement, Forecasting Techniques Primary Data, Question Correlation and Regress Correlation Vs. Determ	Ma , Tests of S s, Time Ser maire and I maire and I sion Analy ination, Ty	easurer found M ries Ana Met Intervie S sis, Me ypes of 0	Good ment a feasur alysis, thods ws, C Statist thod c Corre H	Sample De and Scalin rement, Sca Interpolati of Data C ollection of ical Proces of Least Sq lation and f ypothesis	esign, Random Sam g Techniques aling and Scale Cor on and Extrapolati ollection f Secondary Data, o ssing uares, Regression Their Specific App Testing	nples and Rando nstruction Technon. Cases and Scheo Vs. Correlation, lications.	niques,
Sampling Design. Errors in Measurement, Forecasting Techniques Primary Data, Question Correlation and Regress	Ma , Tests of S s, Time Ser anaire and I sion Analy ination, Ty arametric V les for Tes	easurer ound N ries Ana Met Intervie sis, Me ypes of the Vs. Non sting H	Good ment a feasuralysis, thods ws, C Statist thod of Corre H n-Para ypoth	Sample De and Scalin rement, Sca Interpolati of Data C ollection of ical Proces of Least Sq lation and ypothesis metric Tes esis, Samp	ssign, Random Sam g Techniques aling and Scale Con on and Extrapolati ollection f Secondary Data, of ssing uares, Regression V Their Specific App Testing ts, Procedure for T ling Distribution,	nples and Rando nstruction Technon. Cases and Scheo Vs. Correlation, lications.	niques, dules.
Sampling Design. Errors in Measurement, Forecasting Techniques Primary Data, Question Correlation and Regress Correlation Vs. Determ Tests of Hypothesis, Pa of Statistical Techniqu Square Test, Analysis of	Ma , Tests of S s, Time Sen anaire and I sion Analy ination, Ty arametric V les for Tes of Variance	easurer ound M ies Ana Met Intervie sis, Me /pes of 0 /s. Non sting H and Co	Good nent a Aeasun alysis, thods ws, C Statist thod c Corre Han-Para ypoth ovaria nterp	Sample De and Scalin rement, Sca Interpolati of Data C ollection of ical Proces of Least Sq lation and 7 ypothesis metric Tes esis, Samp nce, Multiv retation of	ssign, Random San g Techniques aling and Scale Cor on and Extrapolati ollection f Secondary Data, of ssing uares, Regression V Their Specific App Testing ts, Procedure for T ling Distribution, variable Analysis f Data	nples and Rando nstruction Technon. Cases and Scheo Vs. Correlation, lications. Cesting Hypothe Sampling Theo	niques, dules.
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Sampling Design. Errors in Measurement, Forecasting Techniques Primary Data, Question Correlation and Regress Correlation Vs. Determ Tests of Hypothesis, Pa of Statistical Techniqu Square Test, Analysis of	Ma , Tests of S s, Time Ser maire and I sion Analy ination, Ty arametric V tes for Tes of Variance yout of a R re Books :	easurer bound M ries Ana Met Intervie sis, Me pes of 0 Vs. Non sting H and Co Is esearch	Good nent a leasural lysis, thods ws, C Statist thod c Corre H n-Para ypoth ovaria nterp Pape	Sample De and Scalin rement, Sca Interpolati of Data C ollection or ical Proces of Least Sq lation and 7 ypothesis metric Tes esis, Samp nce, Multiv retation of r, Techniqu	ssign, Random San g Techniques aling and Scale Cor on and Extrapolati ollection f Secondary Data, of ssing uares, Regression V Their Specific App Testing ts, Procedure for T ling Distribution, variable Analysis T Data tes of Interpretation	nples and Rando nstruction Technon. Cases and Scheo Vs. Correlation, lications. Cesting Hypothe Sampling Theo n.	niques, dules.

List of Audit Courses

Description	Subject Title
	Disaster Management
Audit Course – I	English for research Paper Writing
	Sanskrit for Technical Knowledge

DISASTER MANAGEMENT (Audit Course – I for M. Tech-I Semester)

I Semester :VLSI & ES	-				-		ne: 2022
Course Code	Hours	/Week		Credits		num Marks	
AU 101	L 2	T	Р	C 0	Continuous Internal Assessment	End Exam	TOTA L
Course Outcomes : At the e	_	course	the st	-	be able to		
CO1: Learn to demonstrate a d						k reduction and	
humanitarian response. CO2: Critically evaluate disas multiple perspectives.	ter risk re	eduction	and l	humanitari	an response policy	and practice from	om
CO3: Develop an understandin	ng of star	ndards o	f hum	nanitarian r	esponse and practic	cal relevance ir	1
specific types of disasters and	-			laintai lain 1	esponse and practi		L.
CO4: Critically understand the				esses of dis	aster management	approaches.	
CO5: Planning and programm							untries
they work in	ing in un		ounti	ics, particu		unity of the co	ununes
			TIN	IT - I			
Introduction: Disaster: Definiti and Manmade Disasters: Differer Disaster Prone Areas in Indi and Avalanches; Areas Prone to O Diseases and Epidemics Repercussions of Disasters and of Ecosystem. Natural Disasters:Earthquakes, Volcanism Man-made disaster:Nuclear Reac Epidemics, WarandConflicts. Disaster Preparedness and M DisasterorHazard;EvaluationofRif fromMeteorologicalandOtherAge Risk Assessment Disaster Ris ConceptandElements, DisasterRis	nce, Natur a: Study of Cyclonic a nd Hazan ns,Cyclone tor Meltdo fanagem ask:Applic encies,Meo sk: kReductio	e, Types of Seismi and Coas rds:Econ es,Tsunan own,Indu eent: Pre ationofR diaRepor	and M ic Zon tal Ha <u>UN</u> nomic mis,Fl ustrial <u>UNI</u> paredu emote ts:Go <u>UNI</u> landN	Iagnitude. $Iagnitude.$ $Ies;$ Areas P $zards$ with S $IT - II$ $Damage, L$ $oods, Droug$ $Accidents, G$ $IT - III$ $ness:Monito esensing, Daw vernmentala T - IV fationalDisa $	Prone to Floods and E Special Reference to Loss of Human and A shtsandFamines,Land Dil Slicks andSpills,C pringofPhenomenaTr and CommunityPrep- sterRiskSituation.Te	Droughts, Landsl Tsunami; Post-I nimal Life, Dest IslidesandAvalar DutbreaksofDise riggering a aredness.	ides Disaster ruction aches, ase and
Assessment, Global Co-Operation RiskAssessment.StrategiesforSur		Assessm	ent an	d Warning,	People sParticipatio	nın	
TABA ISSUSSINGIL, SU dicgicsi OLSUL	v I v al.		UN	IT – V			
Disaster Mitigation: Meaning,	Concept	and Stra			Mitigation Emergin	o Trends In Miti	gation
Structural Mitigation and Non-St	-		•		0 0	•	guttom
Text Books :		0	, - <u>c</u>		0		
1. R.Nishith,SinghAK,"D okCompany.	oisasterM	anagem	entinI	ndia:Persp	ectives, issues and st	rategies"'New]	Royalbo
Reference Books :							
1. Sahni,PardeepEt.Al.(Ed	ls.),"Disa	sterMiti	igatio	nExperience	cesandReflections"	,PrenticeHallof	India,
NewDelhi.							
NewDelhi. 2. GoelS.L.,Disaster Adm	inistratio	n and M	lanage	ement Tex	t and		

ENGLISH FOR RESEARCH PAPERWRITING (Audit Course – I for M. Tech-I Semester)

I Semester :VLSI & E					. reen-r Semester		heme : 2022
Course Code	Hours/	Week		Credits	Max	imum Marks	
					Continuous		
AU 101	L	Т	Р	С	Internal	End Exam	TOTAL
110 101					Assessment		
	2	-	-	0	-	-	-
Course Outcomes : A	At the end	of the c	ourse	the studer	nt will be able to		
CO1: Understand that h						bility	
CO2: Learn about what					s and level of feada	Jinty	
CO3: Understand the sl	cills neede	d when	writi	ng a Title I	Ensure the good au	ality of paper at	verv first-
time submission							
				UNIT - I			
Overview of a Resear							
Breaking up Long S					aphs and Sentence	es – Being C	Concise and
Removing Redundancy	– Avoidir	ng Amb					
				UNIT - II			
Essential Components							
Problem – Highlight	Findings	– He	dging	g and Cr	iticizing – Paraph	irasing and P	lagiarism –
Cauterization.				UNIT - II	[
Introducing Review o	of the Li	terature				the Data –	Findings –
Discussion – Conclusio					59 1 11141 9 515 01	the Dutu	1 mango
				UNIT - IV	7		
Key skills needed when	n writing a	ı Title –	Abst	ract – Intro	oduction.		
				UNIT - V			
Appropriate language	to formu	late M	ethod	ology –	Incorporate Result	s – Put forth	Arguments
and draw Conclusions							
Torrt Dooleg :							
Text Books :	6) Writin	T for So	ionaa	Vale Uni	versity Press (availa	ble on Googla	Books
2. Day R (2006) H	,	, ,				Ū.	,
2. Day K (2000) 11			uons		nie i aper, Camorid	50 Oniversity I	1000
Reference Books :							
	98), Hand	lbook c	of Wr	iting for th	he Mathematical So	ciences, SIAM.	Highman's
		sh for	Writ	ing Resea	rch Papers, Spring	ger New Yorl	C Dordrecht

SANSKRIT FOR TECHNICAL KNOWLEDGE

I Semester :VLSI & ES **Scheme : 2022 Course Code Hours/Week Maximum Marks** Credits **Continuous** L Т Р С Internal End Exam TOTAL AU 101 Assessment 2 0 --**Course Outcomes :** At the end of the course the student will be able to **CO1:** Understanding basic Sanskrit language **CO2:**Ancient Sanskrit literature about science & technology can be understood **CO3:** Being a logical language will help to develop logic in students UNIT - I Alphabets in Sanskrit, UNIT - II Past/Present/Future Tense, Simple Sentences UNIT - III Order, Introduction of roots UNIT - IV Technical information about Sanskrit Literature UNIT - V Technical conceptsofEngineering-Electrical, Mechanical, Architecture, Mathematics **Text Books :** 1. "Abhyaspustakam"–Dr. Vishwas, Samskrita-BhartiPublication, NewDelhi **Reference Books :** 1. "TeachYourselfSanskrit"PrathamaDeeksha-VempatiKutumbshastri,RashtriyaSanskritSansthanam,NewDelhi Publication

(Audit Course – I for M. Tech-I Semester)

2. "India'sGloriousScientificTradition"Suresh Soni, Ocean Books(P)Ltd., NewDelhi.

II Semester – VLSI and Embedded Systems (VLSI & ES)

S. No.	Category	Course Title	L	Т	Р	Credits	End Exam Marks	CIA Marks	Total
Ι		Theory							
1.	PC	Analog IC Design	3	-	-	3	60	40	100
2.	PC	Embedded Systems for Internet of Things	3	-	-	3	60	40	100
3.	PE	Professional Elective – III	3	-	-	3	60	40	100
4.	PE	Professional Elective – IV	3	-	-	3	60	40	100
5.	PE	Professional Elective – V	3	-	-	3	60	40	100
6.	AC	Audit Course - II	2	-	-	0	-	-	-
II		Practical							
7.	PCL	Advanced Electronic Design Automation Lab	-	-	3	2	60	40	100
8.	PCL	Embedded IoT Lab	-	-	3	2	60	40	100
			17	-	6	19	420	280	700

ANALOG IC DESIGN (AICD)

II Semester :VLSI &]							ne: 2022
Course Code	Hours	s/Week	- r	Credits	Maximum Ma	arks	
EC 951	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
	3	-	-	3	40	60	100
Sessional Exam Du	-	Irs			-	xam Duration:	
Course Outcomes :			rse the	student wil			
CO1:Acquire a basic ki and layout techniques.				-		odels, analog N	IOS processes
CO2: Analyze the frequ	lency respon	lises of si	ngie st	age amprin	ers.		
CO3: Analyze and desi							
CO4: Design of single circuits, respectively.	stage and	different	tial sta	ge amplifie	rs with and wit	hout current m	iirror
				OSFET Phy			
IV Characteristics, Seco	ond order ef				Ű.	al MOS Transis	tor Models.
				MOS Proc			
Analog CMOS Process							
Fabrication of active de							
Multi-finger transistors	, Passive de		-			oupling, Groun	u Bounce.
I	0:1			nd Current		C	
Large Signal and Small							
Cascode, Folded Casco Mirrors and current mir					es, basic Currer	it Mirrors, Case	ode Current
			•		- Voltago Dofor		
Dynamic Power Dissipa					Voltage Refer		Glitching
Power Dissipation, Stat		issipation	n – Dio	de Leakage	Current, Subthr		
	701		-	onal Ampli			
General Considerations Amplifier, Gain Boostin topologies, familiarity	ng, slew rate	e, Offset	effects	, PSRR, Sta			
Text Books :		ourrey un					
1.Razavi, B., Design of	Analog CM	IOS Integ	grated	Circuits, Ta	ta McGraw Hill	(2008).	
2. Gray, P.R., Hurst, P. Circuits, John Wiley (2)			Meyer	, R.G., Anal	ysis and Design	of Analog Integ	grated
Reference Books :							
1. Allen, P.E. and Holb	erg, D.R., C	CMOS Ar	nalog C	Circuit Desig	gn, Oxford Unive	ersity Press (20	02) 2nd ed.
2. Gregorian, R. and T (2004).	emes, G.C.	, Analog	MOS	Integrated C	Circuits for Signa	l Processing, Jo	hn Wiley
	of Analog	Layout, F	Prentice	e Hall (2005	j).		
. Hastings, A., The Art	0						
. Hastings, A., The Art Question Paper Patter	0						
	n:	n paper s	hall co	nsist of Six	questions out of	which the stude	ent shall

EMBEDDED SYSTEMS IN INTERNET OF THINGS(EIoT)

II Semester :VLSI & ES	5					Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	imum Marks	
					Continuous		
EC 052	L	Т	Р	С	Internal	End Exam	TOTAL
EC 952					Assessment		
	3	-	-	3	40	60	100
Sessional Exam Dura	tion:2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : At							
CO1: Understand the bas							
CO2: Interpret the purpos			l Actu	ators in Io	Т		
CO3:Analyze Various Io							
CO4:Design IoT Projects	s Using A	Arduino)				
CO5: Analyze Raspberry	/-Pi Proc	essor a	nd Ra	spbian Ope	erating Systems		
			Intro	oduction to	IoT:		
	_		_				
Definition and Characteris		•		0	Logical Design, IoT	Enabling Techr	nologies, IoT
Levels and Deployment To	emplates						
Definition of Concer Con	f t			rs and Act		A	Different
Definition of Sensor, Sen types of Actuators, purpos					¥ 1	sensors, Actuat	or, Different
types of Actuators, purpos				g IoT with			
Arduino IDE, Programmi	ng of Ar					er Sensors LCI) Bluetooth
Wi-Fi, ,GPS, RFID with A	0	<i>au</i> 1110, 11	norra		, when, potentionieu		, Diactoolii,
		s Techn	ologie	es and Data	Transmission for lo	т	
Wi-Max, Wi-Fi (802.11),	Bluetoot	h/Blueto	oth si	mart,Zigbee	Zigbee smart, Cell	ular, NFC,Serial	
Transmission, RS-232, RS		C Inter-	Integr	ated Circuit	, Ethernet, CAN bu	s, USB, Firewall	, Serial
ATA, Parallel Transmissio	on						
	1	D: 17 A		aspberry I			
Raspberry Pi Processor, R	aspberry	P ₁ Vs A	rduin	o, Operatin	g system benefits, R	Laspberry P1 Set	up,
Configuration Text Books :							
	lion Mo	dicatti I	ntorna	of Things	: A Hands-On Appr	oach Danarhack	2015
	<i>v i</i>			÷	and Paradigms,201	<u> </u>	,2013
2. RajkumarDhuyya	,meme		ngs.	<u>i meipies a</u>	ind I aradigins,2010	0	
Reference Books :							
1.CharlesBell,Beginnin	g Sensor	Netwo	rks wi	th Arduino	and Raspberry-Pi A	press 2016	
2.Warren Gay, Master	-						
2.Warren Gay, Master		spoen,		51 255,2010			
Web Reference							
https://onlinecourses.nptel	.ac.in/no	c17_cs2	2/cou	rse			
Question Paper Pattern	:						
Internal Assessment: T	The quest	tion pap	er sha	all consist o	of Six questions out	t of which the st	udent
shall answer any Four q	luestions						
End Exam: The question	on paper	shall co	nsist	of Eight a	lestions out of which	ch the student sl	hall
answer any Five questio				8 · 1			

ADVANCED ELECTRONIC DESIGNAUTOMATION LAB (EDAP)

Semester :VLSI & ES	Schem	e: 2022						
Course Code	Ho	ours/We	eek	Credits	Maximum Marks			
EC 962	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL	
	-	-	3	2	40	60	100	
ND EXAM DURATIO	N : 3 Hr	s	L			1		
Course Outcomes :At t	he end of	the cou	rse the	student wi	ll be able to			
CO1: Perform Transient	, AC and	DC ana	lysis o	f CMOS ba	ased circuits			
CO2: Perform Transient	, AC and	DC ana	lysis o	f PASS-tra	nsistor based circ	cuits		
CO3:Perform Transient,	AC and	DC ana	lysis of	Transmiss	ion Gate based c	ircuits		
CO4:Perform Transient,	AC and	DC ana	lysis of	circuits lik	e CS,CG,CD, D	iff Amplifier, O	p-Amp etc	
CO5: Perform DRS,LVS					, , ,	1 /	1 1	
,			•	EXPERIM	IENTS			
1. Transient Analys	is of vario	ous CM	OS bas	ed circuits	(from simple cir	cuits like Invert	er	
to complex circuit								
2. Transient Analys	is of PAS	S Trans	sistor b	ased circuit	ts			
3. Transient Analys MUX etc).							e,	
4. Transient, AC, D								
Operational Amp	lifiers etc	c.). Find	ing CM	IRR (for D	oifferential and O	perational Amp	lifiers) and	
Bandwidth.								
5. Applications base	_		-					
6. DRC, LVS, Para		es Estin	nation 1	from Layou	ut of CMOS base	d circuits.		
nternal Assessment: 40	Μ							
nd Exam: 60M								

EMBEDDED IoT LAB (EIoT(P))

Semester :VLSI & ES	Scheme : 2022						
Course Code	Ho	ours/We	ek	Credits	Maximu	m Marks	
EC 963	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
	-	-	3	2	40	60	100
ND EXAM DURATIO			1				
Course Outcomes :At t							
CO1: Interpret the level	<u> </u>						
CO2: . Interface the I/O							
CO3: Interface the sense	ors and ac	tuators	with A	Tmega con	troller.		
CO4: Perform Interface	Internet a	applicat	ions wi	th Arduino	and Rasp pi pro	cessors	
		LIS	TOF	EXPERIM	IENTS		
1. Utilization and Pract	ice of Ra	sp Pi Er	vironn	nent and Ar	duino Environm	ent	
2. Interfacing on board		-					
3. Interfacing on board							
4. Interfacing laser ligh							
5. Interfacing chemical							
6. Interfacing temperat	ure senso	r with A	Tmega	a controller			
7. Interfacing touch bas	sed sensor	r with A	Tmega	controller			
8. Interfacing displays	with MSF	P430 con	ntroller				
9. Interfacing multiple	sensors w	ith MS	P430 co	ontroller			
10. Interfacing an I/O bo		olled by	using	Raspberry	Pi controller		
nternal Assessment: 40	M						
End Exam: 60M							

PHYSICAL DESIGN AUTOMATION (PDA)

II Semester :VLSI & ES	8					Scheme	: 2022				
Course Code	Hours/	Week		Credits	Max	imum Marks					
EC 052					Continuous						
EC 953 (Professional Elective –	L	Т	Р	С	Internal	End Exam	TOTAL				
(FIOLESSIONAL ELECTIVE – III)					Assessment						
111)	3	-	-	3	40	60	100				
Sessional Exam Dura	tion : 2	Hrs			End Exa	m Duration: 3	Hrs				
Course Outcomes : At					t will be able to						
CO1: Understand of V		0									
CO2: Acquire knowle	<u> </u>				Ŭ						
CO3: Analyze Algori CO4: Analyze High I			Jesigi		011.						
CO4. Analyze High L		1110515.									
		Intr	oduct	tion to VL	SI Design						
Automation, use of VL	SI CAD				Ũ	utational Com	olexity and				
ROBDD; Partitioning a			KL a	algorithm,	FM algorithm, G	roup-migration	algorithm,				
Simulated Annealing an				1.54	· · ·						
Placement, Layout styles		_		0	Assignment	drivan placama	nt Douting:				
Global Routing, detailed					-	-	-				
Tree based Algorithms, I	0	-		is, Line Se	aren, waze Routing	g, Channel Rou	ling, Steller				
		11		Issues in a	circuit layout						
delay models, timing da					•	inimization Ov	ver the Cell				
Routing – Single layer an	_			-	-	, e .					
			-	Compactio	-						
Problem formulation, On	e Dimen	sion co		-		ion, Hierarchic	al				
Compaction, Compaction			-		-						
			High	level synt	hesis						
Introduction to HDL, HD	L to DF	G, oper	ation	scheduling	: constrained and u	nconstrained sc	heduling,				
ASAP, ALAP, List sched	luling, F	orce dir	ected	Scheduling	g, operator binding,	Static Timing	Analysis:				
Delay models, setup time	, hold tii	ne, cyc	le tim	e, critical p	oaths, Topological N	MVS Logical ti	ming				
analysis, False paths, Arr	ival time	e (AT), 1	Requi	red arrival	Time (RAT), Slack	KS					
Text Books :											
1 .Sherwani, N., Algorith			•			r (2005) 3 rd ed					
2. Gerez S.H., Algorithm	s for VL	SI Desi	gn Aı	itomation,	John Wiley (1998						
Reference Books :											
1 .Sarrafzadeh, M. and W	Vong, C.	K., An	Introc	luction to V	VLSI Physical Desi	gn, McGraw H	ill (1996).				
2.Sait, S. M. and Yousset	f, Habib.	VLSI I	Physic	al Design	Automation – Theo	ory and Practice	, World				
Scientific, 2004.			5	0							
Question Paper Pattern	:										
Internal Assessment: T		ion pap	er sha	all consist o	of Six questions out	t of which the st	udent				
shall answer any Four q	-		-								
End Exam: The question		shall co	nsist	of Eight q	uestions out of which	ch the student s	hall				
answer any Five question	0115										

CAD FOR VLSI (CV)

		C		FOR VLS			
II Semester :VLSI & E	1					Scheme	: 2022
Course Code	Hours	Week		Credits	Max	kimum Marks	
					Continuous		
EC 954	L	Т	Р	С	Internal	End Exam	TOTAL
(Professional Elective – III)					Assessment		
111)	3	-	-	3	40	60	100
Sessional Exam Dur	ation : 2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : A	t the end	of the c	ourse	the studer	t will be able to		
CO 1; Understand	the basic	knowle	dge o	of unix con	nmands and prog	ramming skills	•
CO2; Analyze the p	orogramr	ning me	odel o	of perl and	python.		
CO3:Analyze progr	-						
CO4:Analyze case s	studies in	pytho	n ope	rations			
				1 4	* 1 * 1 * * 7		
	1			luction to		TT 11'	וית ויז
Architecture, Basic c Attributes, vi editor, re					tilities, File Syste	em, Handling	Files, File
Autoucs, vi eutor, re	gulai expl	10551011,	SHEII	PERL			
Introduction to Perl, L	iterals.	Variable	type		ntexts. Perl Array	s. Perl Hashes	Operators.
Conditionals, Loops & S			• •		•	<i>, , , , , , , , , ,</i>	, operators,
	Juoroutin	05, 1 1100	, and ,	i ne nanan			
		Ι	DIRE	CTORY			
Directory, Pattern Mat	ching an	d Regu	ılar E	Expressions	s, Accessing Syst	em Resources,	Generating
Reports with Perl	U	U		•			C
				PYTHON			
Introduction to Python,	Fundame	ntals to	Pythe	on, operato	ors and conditions,	regular express	ions, Loops,
working with files, Argu			•	, 1		0 1	, T
	,			RATORY	WORK		
Writing basic command	s in unix,	perl and	d pyth	non. Also v	vrite programs in u	nix, perl and py	thon.
-		-					
Text Books :							
1. Sumitbha Das, U	Jnix: Con	cepts A	nd Ap	plications,	McGraw Hill Edu	cation, 4 th edition	on.
2. Ellie Quigley, Pe	erl by Exa	mple, P	rentic	ce Hall, 5 th	edition, 2014		
3. Mark Lutz, Lear	ning Pyth	on, O'R	eilly	Media, 5th	edition, 2013.		
Question Paper Pattern	n:						
Internal Assessment:			er sha	all consist o	of Six questions ou	t of which the s	tudent
shall answer any Four	-						
End Exam: The questi		shall co	nsist	of Eight q	uestions out of whi	ch the student s	hall
answer any Five questi	ons						

MIXED SIGNAL CIRCUIT DESIGN (MSCD)

II Semester :VLSI & E						Scheme	: 2022
Course Code	Hours	/Week		Credits		ximum Marks	1
EC 955 (Professional Elective –	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
III)	3	-	-	3	40	60	100
Sessional Exam Dura	tion:2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : A	t the end	of the c	ourse	the studer	t will be able to		
CO1: Analyze mathema performance specificatio CO2: Analyze formulate CO3: Use the techniques	ns. s, and so	lves eng	gineer	ing proble	ns in the area of m	ixed-signal desi	ign.
CO4: Analyze a mixed-s			<u> </u>			1	
•	-			ntroductio	n		
Device Models, IC Proce	ess for M	lixed Sig	gnal, (Concepts o	f MOS Theory.		
					Convertors		
Circuit Modeling, Auto	-	-			-	-	-
Fully Differential Compa		Latched	Com	parator, Re	equirements, Static	and Dynamic F	Performanc
SNR and BER, DNL, IN							
	High S	peed A	/D &	D/A Conv	erter Architectur	es	
Flash, Folding, Interpol	ating, p	iplelineo	l, Ny	quist-Rate	D/A Converters,	Thermometer	Coded D/
Converters, Binary Weig	hted D/A	A Conve	rters.				
Implement	ation ar	d Desig	n of H	High Perfor	mance A/D and D	/A Converters	
System Design, Digital C	Compens	ation, N	oise,	and Misma	ttch, Layout and Si	imulation Techn	ologies for
Data Converters.							
			Ad	vanced top	pics		
Multipliers, Oscillators, I				-	-	-	
Frequency Scaling, Phase	e-Locke	d Loops	, Dev	ice Modeli	ng for AMS IC De	sign, Concept o	f AMS
Modeling and Simulation	ı						
Text Books :							
1 . Baker, R.J., Li, H.W (2007) 2nd ed.							
2. Gregorian, R. and Te (2002).							
3.Jespers, P.G. A., Integ Oxford University Pres	-		s: D-	A and A-D	Architectures, An	alysis and Simu	lation,
Reference Books :	_						
1.Plassche, Rudy J.Va	in De, In	tegrated	A-D	and D-A C	Converters, Springe	er (2007), 2nd e	d.
Question Paper Pattern							
Internal Assessment:	-		er sha	all consist o	of Six questions ou	it of which the s	tudent
shall answer any Four of End Exam: The question	-						

EMBEDDED NETWORKS AND PROTOCOLS (ENP)

	S					Scheme	: 2022
Course Code	Hours	Week		Credits	Max	kimum Marks	
EC 956 (Professional Elective – IV)	L	Т	Р	С	Continuous Internal Assessment	End Exam	ΤΟΤΑΙ
1 ()	3	-	-	3	40	60	100
Sessional Exam Dura	ation:2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : A	t the end	of the c	ourse	the studen	t will be able to		
CO1: Understand concept	ots of CA	N prote	cols a	and Etherne	et		
CO2: Understand elemen							
CO3: Analyze industrial			ocols	•			
CO4: Analyze RF comm	unication		DOT	HOPTON	TOCAN		
		INI	ROD	UCTION	TOCAN		
Elements of a networ Connections and networ Using the internet in loc	ork speed	ide Eth	ernet sign c	choices: Se	g a Network: Ha lecting component	ts –Ethernet Co	
0				DED ETH		1	
Exchanging messages u pages that respond to us						namic Data – S	erving web
Nelw/ork secure		Linai	for E	Embedded S	Systems – Using F	TP – Keeping D	
Network secure.	INDU				Systems – Using F		
LIN – Local Interconne Gateways - Managing th buses - I2C Bus - D2B	ct Netwo	STRIA ork - Bas ation la	L NE sic co yers -	CTWORK	ING PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire	- Fail-safe SBC	Devices and
LIN – Local Interconne Gateways - Managing t buses - I2C Bus - D2B	ct Netwo he applic	STRIA ork - Bas ation la RI	L NE sic co yers -	CTWORK ncept of the Safe-by-W	ING PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire ATION	- Fail-safe SBC e Plus – Audiovi	Devices and
LIN – Local Interconne Gateways - Managing t buses - I2C Bus - D2B Radio-frequency comm (passive keyless entry)	ct Netwo he applic unicatior and passi	STRIA ork - Bas ation la main and the state of the state	L NE sic co yers - F CO al and FPMS	CTWORK ncept of the Safe-by-W MMUNIC d external - S (tyre pres	ING PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire ATION Remote control of sure monitoring sy	- Fail-safe SBC e Plus – Audiovi f opening parts - stems) -Wireles	Devices and deo PKE
LIN – Local Interconne Gateways - Managing t buses - I2C Bus - D2B Radio-frequency comm	ct Netwo he applic unicatior and passi	STRIA ork - Bas ation la main and the state of the state	L NE sic co yers - F CO al and FPMS	CTWORK ncept of the Safe-by-W MMUNIC d external - S (tyre pres	ING PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire ATION Remote control of sure monitoring sy	- Fail-safe SBC e Plus – Audiovi f opening parts - stems) -Wireles	Devices and deo PKE
LIN – Local Interconne Gateways - Managing ti buses - I2C Bus - D2B Radio-frequency comm (passive keyless entry) a networks GSM-Bluetoc Text Books : 1 . <i>Multiplexed Networks</i> Paret,John Wiley & Sons	ct Netwo he applic unicatior and passi oth - IEEl for Emb s Ltd- 20	STRIA ork - Bas ation la RH a: intern ve go- ' E 802.1 edded S 07.	L NE sic co yers - F CO al and FPMS 1x - N ystem	CTWORK ncept of the Safe-by-W MMUNIC d external - S (tyre pres IFC (near-f	ING PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire ATION Remote control of sure monitoring sy field communicatio	- Fail-safe SBC e Plus – Audiovi copening parts - stems) -Wireles on). y-Wire, Dominio	Devices and deo PKE s
LIN – Local Interconne Gateways - Managing t buses - I2C Bus - D2B Radio-frequency comm (passive keyless entry) a networks GSM-Bluetoc Text Books : 1 . <i>Multiplexed Networks</i> Paret,John Wiley & Sons 2. <i>Embedded Ethernet a</i>	ct Netwo he applic unicatior and passi oth - IEEl for Emb s Ltd- 20	STRIA ork - Bas ation la RH a: intern ve go- ' E 802.1 edded S 07.	L NE sic co yers - F CO al and FPMS 1x - N ystem	CTWORK ncept of the Safe-by-W MMUNIC d external - S (tyre pres IFC (near-f	ING PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire ATION Remote control of sure monitoring sy field communicatio	- Fail-safe SBC e Plus – Audiovi copening parts - stems) -Wireles on). y-Wire, Dominio	Devices and deo PKE s
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LIN – Local Interconne Gateways - Managing ti buses - I2C Bus - D2B Radio-frequency comm (passive keyless entry) a networks GSM-Bluetoc Text Books : 1 . <i>Multiplexed Networks</i> Paret,John Wiley & Sons 2. <i>Embedded Ethernet an</i> Reference Books : 1. <i>Embedded networking</i> Key old Embedded Syste	ct Netwo he applic unicatior and passi oth - IEEI for Emb s Ltd- 20 nd Intern with CA em Acade	STRIA ork - Bas ation la RH a: intern ve go- 7 E 802.1 Edded S 07. et Comp N and C emy 200 tion pap	L NE sic co yers - Γ CO al and Γ PMS 1x - N ystem olete, CAN = 0	CTWORK ncept of the Safe-by-W MMUNIC d external - S (tyre pres JFC (near-f <i>s</i> - <i>CAN</i> , <i>LI</i> Jan Axelso	NG PROTOCOL e LIN 2.0 protocol /ire - Safe-by-Wire ATION Remote control of sure monitoring sy field communicatio <i>N, Flexray, Safe-b</i> nPenram publicati	- Fail-safe SBC e Plus – Audiovi f opening parts - stems) -Wireles on). y-Wire, Dominio ons	PKE s que an

MICROCONTROLLERS FOR EMBEDDED SYSTEM DESIGN (MESD)

II Semester :VLSI & ES	5					Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	ximum Marks	
EC 957 (Professional Elective – IV)	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
1)	3	-	-	3	40	60	100
Sessional Exam Dura	tion : 2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : At	the end	of the c	course	e the studen	t will be able to		
CO1: Understand ARM A	Architect	ure and	pipe	lining.			
CO2: Analyze ARM proc	essor in	structio	n set a	and thumb	formats.		
CO3: Use ARM program	0			1 0			
CO4: Analyze the memo	ry mana	gement			-	or	
				Architec			
ARM Design Philosoph						Pipeline, Interrup	pts
and Vector Table, Archi	tecture I		-				
				gramming			
Instruction Set: Data Pro	U			-	g Modes, Branch, I	Load, Store	
Instructions, PSR Instruction	ctions, C						
			<u> </u>	, <u> </u>	Model – II		
Thumb Instruction Set:	-	-				-	
Instructions, Single-Reg	ister and					tack	
Simple C Programs usin	a Functi			I Program		Floating Point	
Arithmetic, Assembly C	-				-	-	
Antimietic, Assembly C		-		ry Manag		ion, conditions.	
Cache Architecture, Poli Permissions, Context Sv						anslation, Acces	S
Text Books :							
1 .ARM Systems Develop Dominic Symes, Chris W			-	ing & Optin	nizing System Sof	ftware – Andrew	N. Sloss,
Reference Books :							
1.Embedded Microcompu Cole, 1999, Thomas Lear	•	ems, Re	eal Ti	me Interfac	ing – Jonathan W.	Valvano – Bro	okes /
Question Paper Pattern	:						
Internal Assessment: T	The quest		er sha	all consist o	of Six questions ou	t of which the st	tudent
shall answer any Four q End Exam: The questio answer any Five questio	n paper		nsist	of Eight qu	estions out of whi	ch the student s	hall

PRINCIPLES OF DISTRIBUTED EMBEDDED SYSTEMS (PDES)

II Semester :VLSI & E						Scheme	: 2022
Course Code	Hours	Week		Credits	Max	ximum Marks	
EC 958 (Professional Elective –	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
IV)	3	-	-	3	40	60	100
Sessional Exam Dura	tion:2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : At	the end	of the c	ourse	the studer	t will be able to		
CO1: Understand C lang	lage and	assemt	ly pr	ogramming	7		
CO2: Understand Object							
CO3: Analyzesoftware m	odeling	fundam	entals	5.			
CO4: Analyze embedded	softwar						
		REAI	L-TIN	IE ENVIR	ONMENT		
Real-time computer sys							_
global time – internal an							
communication – tempo						wareness – real	-time
communication – event	triggere	d – rate	const	rained - til	me triggered		
	RF	EAL-TI	ME (DPERATI	NG SYSTEMS		
Inter component com	nunicati	on – tas	k mar	nagement -	- dual role of time -	 inter task inter 	actions –
process input/output -							
			CVC	TEM DES			
Scheduling problem -	static &	dynami				idation time t	riggered
architecture		aynann	Serie	duning – s	ystem design – van		liggered
		INT	ROD	UCTION	TO CAN		
Introduction to CAN Ope	en – CAl	N open s	standa	ard – Objec	t directory – Elect	ronic Data Shee	ts &
Devices.							
				STANDA			
Configuration Files – Se	ervice Da	ata Obje	ctives	s – Networ	k management CA	N open message	es –
Device Profile Encoder							
Text Books :							
1 .HermannKopetz, "Rea	l–Time s	systems	– De	sign Princi	ples for distributed	Embedded	
Applications", 2nd Editio				-	-		
Reference Books :							
1GlafP.Feiffer, Andrew	Avre and	Christi	an Ke	vold. "Em	bedded Networkin	g with CAN and	1
CAN open", Copperhill I							
Question Paper Pattern							
Internal Assessment:T		ion pape	er sha	ll consist o	f Six questions out	t of which the st	udent shall
answer any Four questi							
End Exam: The question	n paper	shall co	nsist	of Eight q	uestions out of whi	ch the student s	hall
answer any Five questic				0 1			

VLSI DESIGN FOR TESTABILITY (VDFT)

	S					Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	kimum Marks	
EC 959 (Professional Elective – V)	L	Т	Р	С	Continuous Internal Assessment	End Exam	TOTAL
V)	3	-	-	3	40	60	100
Sessional Exam Dura	tion:2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : A	t the end	of the c	ourse	the studen	t will be able to		
CO1: Understand all the					rcuits		
CO2: Understand the DF	A				_		
CO3: Analyze logic and CO4: Analyze test gener				LSI circuit	S		
CO4. Analyze test gener							
				uction to 7	6		
Importance of Testing, in VLSI Testing, Fault 1	-	-		•	-	VLSI Testing-	Challenges
		I	Desig	n for Testa	bility		
Introduction, Testabilit Analysis, Simulation-Ba		sisS	COA	P Testabil		bability-Based	Testability
		Log	ic an	d Fault Si	mulation		
			,	u i uun on	nulation		
Logic Simulation for Dea Models-Gate-Level Netv	0		, Faul bols,	lt Simulatio Logic Elen	on for Test and Dia ment Evaluation	gnosis, Simulat	ion
6	Fest Gen	gic Sym	, Faul bols, Tes Bool	t Simulatio Logic Elen st Generat ean differe	on for Test and Dia ment Evaluation ion nce, untestable fau	ults, Designing	a Stuck-At
Introduction, Random 7 ATPG for Combinationa	Fest Gen	gic Sym eration, A Na	, Faul bols, Tes Bool aive A	t Simulatio Logic Elen st Generat ean differe	on for Test and Dia ment Evaluation ion nce, untestable fau rithm, A Basic ATP	ults, Designing	a Stuck-At
Models-Gate-Level Netv Introduction, Random 7 ATPG for Combinationa	Cest Gen Cest Gen l Circuits Cern Ger Delay Fa	eration, A Na Leration ult Tes	, Faul bols, Bool aive A ogic I E ting;	It Simulation Logic Elem at Generat ion ean differe ATPG Algon Built-In Se xhaustive Output R	on for Test and Dia ment Evaluation ion nce, untestable fau rithm, A Basic ATP If-Test Testing, Pseudo-H esponse Analysis	ults, Designing G Algorithm, D Random Testing	a Stuck-At Algorithm, g, Pseudo-
Models-Gate-Level Netv Introduction, Random T ATPG for Combinationa PODEM. Introduction, Test Patt Exhaustive Testing, D	Cest Gen Cest Gen l Circuits Cern Ger Delay Fa	eration, A Na Leration ult Tes	, Faul bols, Bool aive A ogic I E ting;	It Simulation Logic Elem at Generat ion ean differe ATPG Algon Built-In Se xhaustive Output R	on for Test and Dia ment Evaluation ion nce, untestable fau rithm, A Basic ATP If-Test Testing, Pseudo-H esponse Analysis	ults, Designing G Algorithm, D Random Testing	a Stuck-At Algorithm, g, Pseudo-
Models-Gate-Level Netv Introduction, Random 7 ATPG for Combinationa PODEM. Introduction, Test Patt Exhaustive Testing, D Transition Count Testin	Fest Gen l Circuits ern Ger g, Signat	gic Sym eration, A Na eration ult Tes ult Tes ure Ana Wu, Xia	, Faul bols, Tes Bool aive A ogic I ting; alysis,	It Simulation Logic Elem to the temperature an differe ATPG Algon Built-In Se xhaustive Output R Logic BIS Wen, "VLS	on for Test and Dia nent Evaluation ion nce, untestable fau tithm, A Basic ATP If-Test Testing, Pseudo-H tesponse Analysis T Architectures	ults, Designing G Algorithm, D Random Testing Ones Cour	a Stuck-At Algorithm, g, Pseudo- nt Testing,
Models-Gate-Level Netv Introduction, Random T ATPG for Combinationa PODEM. Introduction, Test Patt Exhaustive Testing, D Transition Count Testin Text Books : 1 .Laung-Terng Wang, Char	Fest Gen l Circuits ern Ger g, Signat	gic Sym eration, A Na eration ult Tes ult Tes ure Ana Wu, Xia	, Faul bols, Tes Bool aive A ogic I ting; alysis,	It Simulation Logic Elem to the temperature an differe ATPG Algon Built-In Se xhaustive Output R Logic BIS Wen, "VLS	on for Test and Dia nent Evaluation ion nce, untestable fau tithm, A Basic ATP If-Test Testing, Pseudo-H tesponse Analysis T Architectures	ults, Designing G Algorithm, D Random Testing Ones Cour	a Stuck-At Algorithm, g, Pseudo- nt Testing,
Models-Gate-Level Netv Introduction, Random T ATPG for Combinationa PODEM. Introduction, Test Patt Exhaustive Testing, D Transition Count Testin Text Books : 1 .Laung-Terng Wang, Cha Testability", 1st Edition, M	Fest Gen Fest Gen l Circuits cern Ger Delay Fa g, Signat eng-Wen forgan Ka rawal, "E	gic Sym eration, A Na neration ult Tes ure Ana Wu, Xia ufmann, ssentials	, Faul bols, Tes Book aive A ogic I E ting; alysis, oqing 2006.	It Simulatic Logic Elen t Generat ean differe ATPG Algor Built-In Se Xhaustive Output R Logic BIS Wen, "VLS	on for Test and Dia nent Evaluation ion nce, untestable fau tithm, A Basic ATP If-Test Testing, Pseudo-H tesponse Analysis T Architectures	ults, Designing G Algorithm, D Random Testing Ones Cour d Architectures: I	a Stuck-At Algorithm, g, Pseudo- nt Testing, Design for
Models-Gate-Level Netv Introduction, Random T ATPG for Combinationa PODEM. Introduction, Test Patt Exhaustive Testing, D Transition Count Testin Text Books : 1 .Laung-Terng Wang, Cha Testability", 1st Edition, M Reference Books : 1.M.L. Bushnell, V. D. Ag	Fest Gen Cest Gen l Circuits cern Ger belay Fa g, Signat eng-Wen organ Ka rawal, "E ademic P	gic Sym eration, A Na neration ult Tes ure Ana Wu, Xia ufmann, ssentials	, Faul bols, Tes Book aive A ogic I E ting; alysis, oqing 2006.	It Simulatic Logic Elen t Generat ean differe ATPG Algor Built-In Se Xhaustive Output R Logic BIS Wen, "VLS	on for Test and Dia nent Evaluation ion nce, untestable fau tithm, A Basic ATP If-Test Testing, Pseudo-H tesponse Analysis T Architectures	ults, Designing G Algorithm, D Random Testing Ones Cour d Architectures: I	a Stuck-At Algorithm, g, Pseudo- nt Testing, Design for
Models-Gate-Level Netv Introduction, Random T ATPG for Combinationa PODEM. Introduction, Test Patt Exhaustive Testing, D Transition Count Testin Text Books : 1 .Laung-Terng Wang, Che Testability", 1st Edition, M Reference Books : 1.M.L. Bushnell, V. D. Ag VLSI Circuits", Kluwer Ac	Fest Gen Fest Gen l Circuits cern Ger belay Fa g, Signat eng-Wen forgan Ka forgan Ka rawal, "E cademic P the quest ons	gic Sym eration, A Na eration ult Tes ure Ana ult Tes ure Ana wu, Xia ufmann, ssentials ublisher	, Faul bols, Tes Bool aive A ogic I E ting; alysis, oqing 2006. of Ela s, 200 er sha	It Simulation Logic Elem A Generat ean differe A TPG Algor Built-In Se xhaustive Output R Logic BIS Wen, "VLS wen, "VLS ectronic Tes 0	on for Test and Dia nent Evaluation ion nce, untestable fau tithm, A Basic ATP If-Test Testing, Pseudo-F tesponse Analysis T Architectures I Test Principles and ting for Digital, Mer	ults, Designing PG Algorithm, D Random Testing Ones Cour d Architectures: I mory and Mixed S	a Stuck-At Algorithm, g, Pseudo- nt Testing, Design for Signal

VLSI SIGNAL PROCESSING (VS)

II Semester :VLSI & E	S					Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	kimum Marks	
					Continuous		
EC 960	L	Т	Р	С	Internal	End Exam	TOTAL
(Professional Elective –					Assessment		
V)	3	-	-	3	40	60	100
Sessional Exam Dura	ation : 2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : A	t the end	of the c	ourse	the studer	t will be able to		
CO1: Apply the principle	es of DF	G in DS	P arcl	hitectures			
CO2: Apply pipelining a					d IIR systems to ac	chieve high spee	ed and
Lowpower	1	Ŧ	U		J	0 1	
CO3: Solve Register m	inimizati	on, retir	ning,	folding tec	hniques for the giv	en digital filter.	
CO4: Understand the ov	erview F	IR filter	Syste	olic archite	cture design.		
	Introdu	ction to) Dig	ital Signal	Processing System	ms	
Introduction, Typical D			0	0	0.		
technologies, Represent					i uemanus anu scar	eu CMOS	
teennologies, represent			_	ration Bou	ınd		
Introduction, Data Flow	Graph F	Represei				Bound, Algorith	hms
for computing iteration							
		Pipelin	ing a	nd Paralle	l Processing		
Introduction, Pipelinir						ning and Paralle	1
Processing for low por	wer						
					d Unfolding		
Introduction, Definition							
algorithm for unfolding							
techniques, Register mi and retiming, Application				remiecture	, Folding of multila	ate systems. On	notunig
and retining, Application	0115 01 011			Architectu	re Design		
Introduction, System ar	ray desig					ion of schedulin	g
vector, Matrix-matrix n							
representations containing	ing delay	s.		_			
Text Books :							
1 .Keshab K. Parthi, VI		al Signa	l Proo	cessing- Sy	stem Design and I	mplementation,	
WileyInter Science.	1998.						
2.Kung S. Y, H. J. While	e House,	T. Kaila	th, V	LSI and M	odern Signal proce	ssing, Prentice I	Hall, 1985.
Reference Books :							
	Taividia	Dagian	ofA	nalog Dig	tol VI SI Circuita f	~~~~	
1 Jose E. France, Yannis Telecommunications and						01	
Question Paper Pattern	-	1000331	<u>6</u> , 1		.,.//		
Internal Assessment:T		ion nane	er sha	ll consist o	f Six questions out	of which the st	udent shall
answer any Four quest		un pap	-1 511a			or which the st	adom shall
End Exam: The question		shall co	nsist	of Eight q	uestions out of whi	ch the student sl	hall
answer any Five question				5 1			

MEMORY DESIGN AND TESTING (MDT)

II Semester :VLSI & ES	8					Scheme	: 2022
Course Code	Hours/	Week		Credits	Max	cimum Marks	
					Continuous		
EC 961 (Professional Elective –	L	Т	Р	С	Internal	End Exam	TOTAL
(Professional Elective – V)					Assessment		
•)	3	-	-	3	40	60	100
Sessional Exam Dura	tion : 2	Hrs			End Exa	m Duration: 3	Hrs
Course Outcomes : At	t the end	of the c	ourse	e the studen	t will be able to		
CO1: Understand Bas				Design and	Technology.		
CO2: AnalyzeRAM a							
CO3: Analyze On-Ch	± '						
CO4: Interpret Laplac		-					
CO5: Analyze High-							
Desing of Comison dusts				•	Chip Design	hina Managar	Call Amore
Basics of Semiconducto							
Peripheral Circuit, I/O In		U		•		•	
Architectures of memory						=	-
Technology, Ferroelectri Memory Design and Teol		огу, Баз	sic U	peration o	I Flash Memory	Cells, Advalice	s in riash-
Memory Design and Tech	0.	- C D A N/	I Dec	ion and T	ahmalaan 9 DDAI	<u>л</u>	
Devices, NMOS Static (0	chnology & DRA		ory Circuits
Scaling Law,High-Densi			-				-
Standard DRAM, Basic (•		-				
Multiplexing, Fundament	-		-				
Write and Relevant Circ							
Circuits, High Signal-to					•	• ·	1 0
Design, Data-Line Noise				U	ind Teennology,	riends in ringh	biit itatio
Design, Data Line House	iteaueri			Voltage G	enerators		
Substrate-Bias Voltage (VBB) Ge		-	8		Down-Converter	Half-VDD
Generator, Examples of A	,			0 1	e e		, 11uii + 22
			-		tem Memories		
Hierarchical Memory Sys				-		formance Stand	lard
DRAMs, Embedded Mer		•	•	•	0 0		
Dissipation in a RAM Su							
			-		nory Circuits		Chounts.
Design Issues for Ultra-L				0	•	reshold Current	. Stable
Memory-Cell Operation,		0					
Supply Standardization, V				-	-		
Ultra-Low-Voltage SOI		., , 0100					
Text Books :							
1.Itoh, K., VLSI Memor	v Chin T	Design	Sprin	ger (2006)			
	, omp i		~Pim	2000)			

2.Sharma, A. K., Semiconductor Memories: Technology, Testing and Reliability, Wiley- IEEE press (2002).

3.Adams, R. D., High performance Memory Testing: Design Principles, Fault Modeling and Self-Test, Springer (2002).

4.Sharma, A. K., Advanced Semiconductor Memories: Architecture, Design and Applications, John Wiley (2002).

5.Prince, B., Semiconductor Memories: A handbook of Design, Manufacture and Application, John Wiley (1996) 2nd ed.

Reference Books :

1. Plassche, Rudy J. Van De, Integrated A-D and D-A Converters, Springer (2007), 2nd ed.

Question Paper Pattern:

Internal Assessment: The question paper shall consist of **Six** questions out of which the student shall answer any **Four** questions

End Exam: The question paper shall consist of **Eight** questions out of which the student shall answer any **Five** questions

List of Audit Courses

Description	Subject Title
	Pedagogy Studies
Audit Course – II	Personality Development through Life Enlightenment Skills
	Stress Management by Yoga

PEDAGOGYSTUDIES (Audit Course – II for M. Tech-II Semester)

II Semester :VLSI & E	N	000110	• -		Tech-II Semest		heme : 2022
Course Code Hours/Week			Credits Maximum Marks				
					Continuous		
	L	Т	Р	С	Internal	End Exam	TOTAL
AU 102					Assessment		
	2	-	-	0	-	-	-
Course Outcomes : A	t the end	of the c	ourse	the studer	t will be able to		
CO1: What pedagogical	practices	arebeing	gused	byteachers	informalandinform	alclassroomsin	
Developing countries?							
CO2: Whatistheevidence	eontheeff	ectiven	essoft	hesepedag	ogicalpractices, inw	hatconditions,	
And with what population	on of learn	ners?					
CO3:Howcanteacheredu	cation(cu	urriculu	mand	practicum)	andtheschoolcurric	ulumand	
Guidance materials best	support e	effective	peda	igogy?			
				UNIT - I			
Introduction and Meth							
terminology Theories of lea Overview of methodology			n, Tea	cher educat	ion. Conceptual fram	ework, search qu	iestions.
	and Searc	ning.		UNIT - II			
Thematic OverviewPed	agogicalpi	racticesa	rebeir	ngusedbytea	chersinformalandinf	ormalclassrooms	in
developing countries. Curr	iculum,Te	acher ed	lucatio	on.			
				UNIT - II	[
Pedagogical Practices a		_	-		—		
Methodology for the in dep	-						
(curriculum and practicum)				-			
Theory of change. Strength theory and pedagogical appropriate theory and pedagogical approximately a			•			•	'edagogic
	ji oaches.	I cachers		UNIT - IV		liategies.	
Professional Developm	ent• Alig	nment w				support Peer sur	nort
Support from the head teac							
resources and large class si	zes.						
Research Gaps and Fut	turo Diro	otiona	Doca	UNIT - V		Topohor advast	on
Curriculum and assessmen				-		, reacher educati	011,
	., 1990111	inacioni a	100 100	curen impa			
Text Books :							
1. AckersJ,HardmanF(2)	001)Class	sroomin	terac	tioninKeny	anprimaryschools,	Compare,31(2):	245-261.
2. AgrawalM(2004) cur				-		-	
Studies, 36 (3): 361-379.				1			
Reference Books :							
1. Akyeampong K (200	03) Teach	ner trair	ning i	n Ghana -	does it count? M	ulti-site teacher	education
research project(MUST)	ER)count	ryrepor	t1.Lo	ndon:DFII).		
2. Akyeampong K, Luss maths and reading in Af JournalEducationalDeve	rica: Doe	s teache	er pre	paration co	· · ·	ing and learning	g of basic

PERSONALITYDEVELOPMENT THROUGHLIFEENLIGHTENMENT SKILLS (Audit Course – IIfor M. Tech-II Semester)

II Semester : VLSI & ES	5					Scl	heme : 2022
Course Code Hours/Week			Credits				
AU 102	L	T	Р	С	Continuous Internal Assessment	End Exam	TOTAL
	2	-	-	0	-	-	-
Course Outcomes : At	the end	of the c	ourse	the studer	t will be able to		I
CO1: Study of Shrimad-	Bhagwad	d-Geeta	will	help the stu	dent in developing	his personality	and
Achieve the highest goal	in life			-			
CO2: The person who ha	as studied	d Geeta	will l	ead the nat	ion and mankind to	peace and pros	sperity
CO3: Study of Neetishat	akam wi	ll help i	n dev		rsatile personality of	of students	
				UNIT - I			
Neetisatakam-Holistic deve	-	-	nality				
• Verses-19,20,2		,					
• Verses-29,31,3	· ±		n)				
• Verses-26,28,6	3,65(virt	ue)					
				UNIT - II			
Neetisatakam-Holistic deve	-	-	nality				
• Verses-52,53,5							
• Verses-71,73,7	5,78(do'	s)					
				UNIT -III			
Approach to day to day wor			0.17	× 4.1 47	7 40		
ShrimadBhagw		-					
Chapter3-Verse			Chapt	er6-Verses	5,13,17, 23, 35,		
Chapter18-Vers	ses45,46	,48.					
<u>Ctatamanta afle a si alta arala da</u>				UNIT - IV			
Statementsofbasicknowledg		Chapta	$n \mathcal{N}$		69		
ShrimadBhagw Chapter12 Ver				erses50,02,	08		
Chapter12-Vers	ses15,14	,13,10,1	/,10				
				UNIT - V			
Personality of Role mode		ad Bhag	gwad (Geeta:			
Chapter2-Verses1							
Chapter3-Verses3							
Chapter4-Verse	, ,						
Chapter18–Ver	ses37,38	3,63					
Text Books :							
1. "SrimadBhagav		•		(D 1 1)	D		
SwamiSwarupa	inandaA	dvaitaA	shran	n(Publication	onDepartment),Kol	kata.	
Defenses Desite							
Reference Books :				~~~*			
1. Bhartrihari'sTh		· · ·	•	0	nanam,NewDelhi.		
vallagya)byP.G	iopinatin,	Nashtri	yasal	iski uSansti	ianani, new Denn.		

STRESS MANAGEMENT BY YOGA (Audit Course – II for M. Tech-II Semester)

II Semester :VLSI &	ES					Sc	heme : 2022
Course Code	Hours/	Hours/Week			Maximum Marks		
AU 102	L	Т	ГР	С	Continuous Internal Assessment	End Exam	TOTAL
	2	-	-	0	-	-	-
Course Outcomes :	At the end	of the c	course	e the studen	t will be able to		
CO1: Develop healthy	mind in a	healthy	body	thus impro	oving social health	also	
CO2: Improve efficien	су						
				UNIT - I			
Definitions of Eight pa	ths of yog.	(Ashtar	nga)				
Yam and Niyam.				UNIT -II			
i ani ana i viyani.				UNIT - III			
Do`s and Don'ts in life i) Ahinsa, satya, a ii) Shaucha, santo Asanand Pranayam i) Various yog poses ar	astheya,bra sh, tapa, sv	vadhyay	y, ishv	warpranidh UNIT - IV UNIT - V	an		
ii) Regularization of br				•	Types of pranayam	1	
Text Books : 1. 'Yogic Asanas	for Group	Trainin	g-Part	t-I": Janard	an Swami Yogabh	yasi Mandal, Na	agpur
Reference Books :							
1. "Rajayogaorcon Department),K		Internal	Natu	re"bySwam	iVivekananda,Ad	vaitaAshrama (I	Publication